



TEMPERATURE DEPENDENT PROBE STATION

TDPS-9500



PROBE STATION can be used for current-voltage characteristics of electronic devices such as solar cell, photodiode, sensor and thin film transistors. Probe station is designed according to below technical properties.

Technical Datasheet

XYZ manipulators (2 or 3)

Vacuum chuck

Temperature chuck

Temperature controller

Temperature range: RT- 400 °C

Microscope for thin film transistor applications
High resolution camera: 5 MPA
Magnification: 130X
Monitor

Probe pin: Spring pin